

Notice of References Cited

Application/Control No.

10/579,146

Applicant(s)/Patent Under
Reexamination
MAHONEY ET AL.

Examiner

Larry E. Waggle, Jr

Art Unit

3775

Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,443,514 A	08-1995	Steffee, Arthur D.	128/898
*	B	US-5,658,336 A	08-1997	Pisharodi, Madhavan	623/17.16
*	C	US-6,080,158 A	06-2000	Lin, Chih-I	606/247
*	D	US-6,174,311 B1	01-2001	Branch et al.	606/86A
*	E	US-2002/0016592 A1	02-2002	Branch et al.	606/61
*	F	US-2002/0165550 A1	11-2002	Frey et al.	606/85
*	G	US-2003/0149438 A1	08-2003	Nichols et al.	606/99
*	H	US-6,648,895 B2	11-2003	Burkus et al.	606/90
*	I	US-6,666,866 B2	12-2003	Martz et al.	606/86A
*	J	US-2004/0153065 A1	08-2004	Lim, Roy K.	606/053
*	K	US-2005/0027360 A1	02-2005	Webb et al.	623/017.11
*	L	US-6,991,654 B2	01-2006	Foley, Kevin T.	623/17.16
*	M	US-7,618,423 B1	11-2009	Valentine et al.	606/99

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 0217823 A1	03-2002	World Intellect	HAN J et al.	
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U					
	V					
	W					
	X					

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.